

# LMK03000/LMK03000C/LMK03001/LMK03001C

## Precision Clock Conditioner with Integrated VCO

### General Description

The LMK03000/LMK03000C/LMK03001/LMK03001C precision clock conditioners combine the functions of jitter cleaning/reconditioning, multiplication, and distribution of a reference clock. The devices integrate a Voltage Controlled Oscillator (VCO), a high performance Integer-N Phase Locked Loop (PLL), a partially integrated loop filter, three LVDS, and five LVPECL clock output distribution blocks.

The VCO output is optionally accessible on the Fout port. Internally, the VCO output goes through an Input Divider to feed the various clock distribution blocks.

Each clock distribution block includes a programmable divider, a phase synchronization circuit, a programmable delay, a clock output mux, and an LVDS or LVPECL output buffer. This allows multiple integer-related and phase-adjusted copies of the reference to be distributed to eight system components.

When configured as a clock generator with a wide loop bandwidth, a high phase detector frequency, and a low noise clock source the LMK03000C/LMK03001C features jitter performance of 200 fs RMS (10 Hz - 20 MHz). When configured as a jitter cleaner, the LMK03000C/LMK03001C features jitter performance of 400 fs RMS (12 kHz - 20 MHz) and the LMK03000C/LMK03001C 800 fs RMS (12 kHz - 20 MHz).

The clock conditioners come in a 48-pin LLP package and are footprint compatible with other clocking devices in the same family.

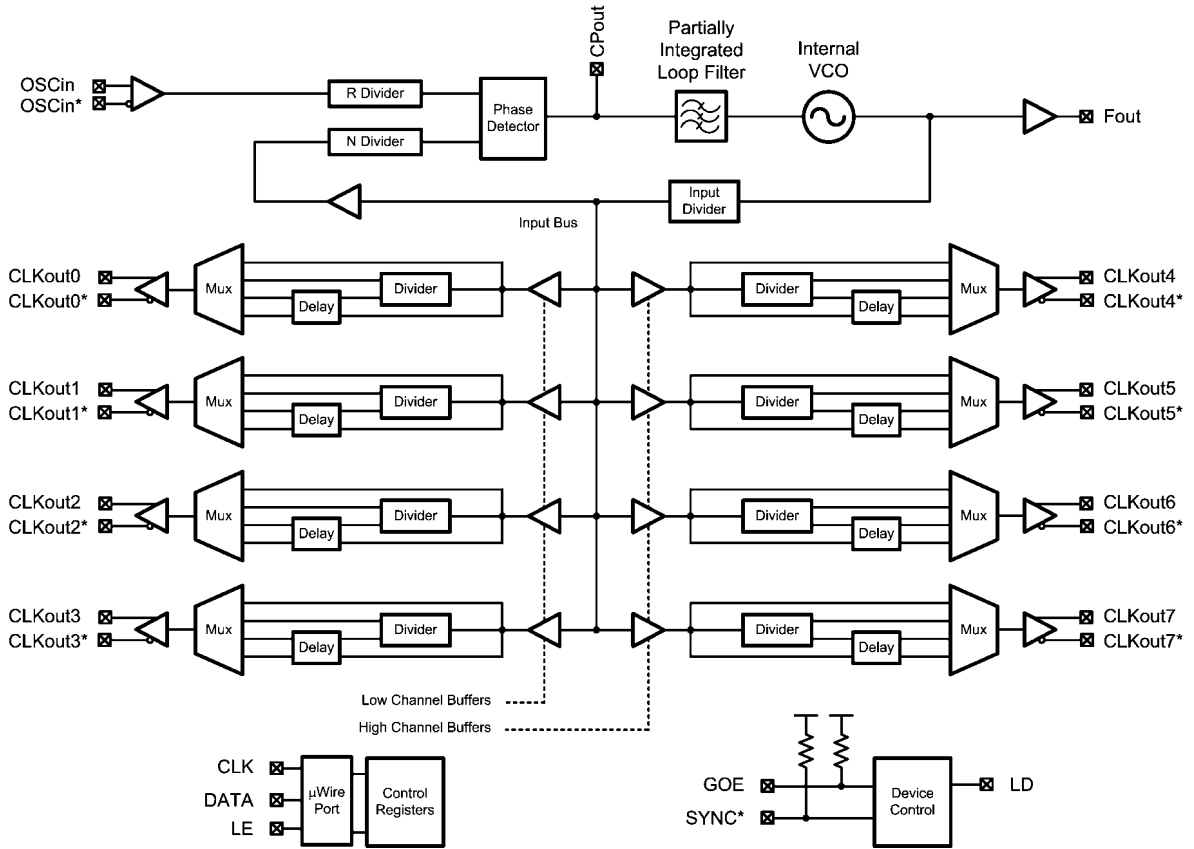
### Features

- Integrated VCO with very low phase noise floor
- Integrated Integer-N PLL with outstanding normalized phase noise contribution of -224 dBc/Hz
- Clock generator performance (10 Hz - 20 MHz)
  - LMK03000C/LMK03001C: 200 fs RMS jitter
- Two jitter cleaner performance grades (12 kHz to 20 MHz)
  - LMK03000/LMK03001: 800 fs RMS jitter
  - LMK03000C/LMK03001C: 400 fs RMS jitter
- Two VCO frequency plans
  - LMK03000/LMK03000C: 1185 to 1296 MHz
  - LMK03001/LMK03001C: 1470 to 1570 MHz
- Clock output frequency range of 1 to 785 MHz
- 3 LVDS and 5 LVPECL clock outputs
- Partially integrated loop filter
- Dedicated divider and delay blocks on each clock output
- Pin compatible family of clocking devices
- 3.15 to 3.45 V operation
- Package: 48 pin LLP (7.0 x 7.0 x 0.8 mm)

### Target Applications

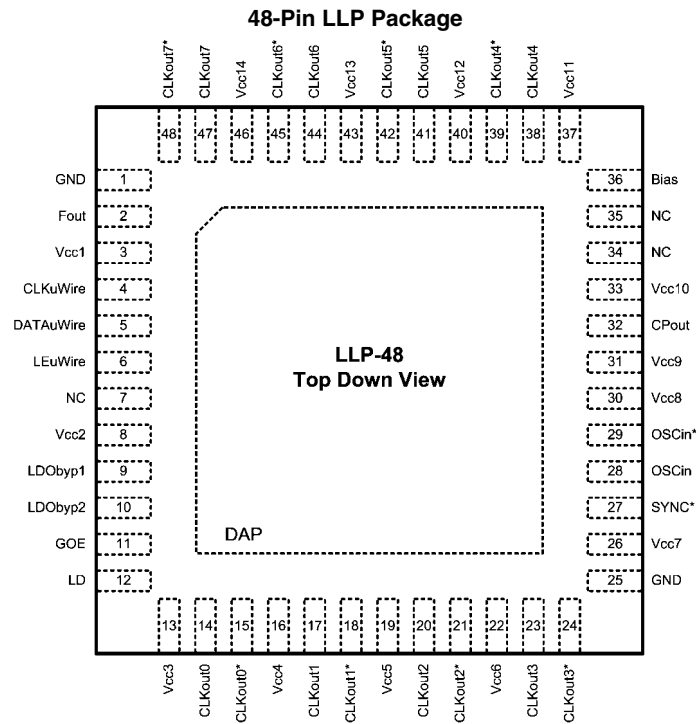
- Data Converter Clocking
- Networking, SONET/SDH, DSLAM
- Wireless Infrastructure
- Medical
- Test and Measurement
- Military / Aerospace

# Functional Block Diagram



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# Connection Diagram



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## Pin Descriptions

Pin #	Pin Name	I/O	Description
1, 25	GND	-	Ground
2	Fout	O	Internal VCO Frequency Output
3, 8, 13, 16, 19, 22, 26, 30, 31, 33, 37, 40, 43, 46	Vcc1, Vcc2, Vcc3, Vcc4, Vcc5, Vcc6, Vcc7, Vcc8, Vcc9, Vcc10, Vcc11, Vcc12, Vcc13, Vcc14	-	Power Supply
4	CLKuWire	I	MICROWIRE Clock Input
5	DATAuWire	I	MICROWIRE Data Input
6	LEuWire	I	MICROWIRE Latch Enable Input
7, 34, 35	NC	-	No Connection to these pins
9, 10	LDObyp1, LDObyp2	-	LDO Bypass
11	GOE	I	Global Output Enable
12	LD	O	Lock Detect and Test Output
14, 15	CLKout0, CLKout0*	O	LVDS Clock Output 0
17, 18	CLKout1, CLKout1*	O	LVDS Clock Output 1
20, 21	CLKout2, CLKout2*	O	LVDS Clock Output 2
23, 24	CLKout3, CLKout3*	O	LVPECL Clock Output 3
27	SYNC*	I	Global Clock Output Synchronization
28, 29	OSCin, OSCin*	I	Oscillator Clock Input; Must be AC coupled
32	CPout	O	Charge Pump Output
36	Bias	I	Bias Bypass
38, 39	CLKout4, CLKout4*	O	LVPECL Clock Output 4
41, 42	CLKout5, CLKout5*	O	LVPECL Clock Output 5
44, 45	CLKout6, CLKout6*	O	LVPECL Clock Output 6
47, 48	CLKout7, CLKout7*	O	LVPECL Clock Output 7
DAP	DAP	-	Die Attach Pad is Ground

## Absolute Maximum Ratings (Notes 1, 2)

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/ Distributors for availability and specifications.

Parameter	Symbol	Ratings	Units
Power Supply Voltage	$V_{CC}$	-0.3 to 3.6	V
Input Voltage	$V_{IN}$	-0.3 to ( $V_{CC} + 0.3$ )	V
Storage Temperature Range	$T_{STG}$	-65 to 150	°C
Lead Temperature (solder 4 s)	$T_L$	+260	°C
Junction Temperature		125	°C

## Recommended Operating Conditions

Parameter	Symbol	Min	Typ	Max	Units
Ambient Temperature	$T_A$	-40	25	85	°C
Power Supply Voltage	$V_{CC}$	3.15	3.3	3.45	V

**Note 1:** "Absolute Maximum Ratings" indicate limits beyond which damage to the device may occur, including inoperability and degradation of device reliability and/or performance. Functional operation of the device and/or non-degradation at the Absolute Maximum Ratings or other conditions beyond those indicated in the Recommended Operating Conditions is not implied. The Recommended Operating Conditions indicate conditions at which the device is functional and the device should not be operated beyond such conditions.

**Note 2:** This device is a high performance integrated circuit with ESD handling precautions. Handling of this device should only be done at ESD protected work stations. The device is rated to a HBM-ESD of >2 kV, a MM-ESD of >200 V, and a CDM-ESD of >1.2 kV.

## Package Thermal Resistance

Package	$\theta_{JA}$	$\theta_{J-PAD}$ (Thermal Pad)
48-Lead LLP (Note 3)	27.4° C/W	5.8° C/W

**Note 3:** Specification assumes 16 thermal vias connect the die attach pad to the embedded copper plane on the 4-layer JEDEC board. These vias play a key role in improving the thermal performance of the LLP. It is recommended that the maximum number of vias be used in the board layout.

## Electrical Characteristics

(3.15 V  $\leq V_{CC} \leq$  3.45 V, -40 °C  $\leq T_A \leq$  85 °C; Differential Inputs/Outputs; except as specified. Typical Values are for  $T_A = 25$  °C,  $V_{CC} = 3.3$  V)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>Current Consumption</b>						
$I_{CC}$	Power Supply Current (Note 4)	Entire Device (no emitter resistors placed)		144.4		mA
		CLKout0 & CLKout4 Enabled in Bypass Mode				
		All Outputs Off		86.0		
$I_{CCPD}$	Power Down Current	POWERDOWN = 1		1		mA
<b>Reference Oscillator</b>						
$f_{OSCin}^{square}$	Reference Oscillator Input Frequency Range for Square Wave	AC coupled; Differential ( $V_{OD}$ )	1		200	MHz
$V_{OSCin}^{square}$	Square wave input voltage for OSCin and OSCin*		0.2		1.6	V <sub>pp</sub>
<b>PLL</b>						
$f_{COMP}$	Phase Detector Frequency				40	MHz
$I_{SRCECPout}$	Charge Pump Source Current	$V_{CPout} = V_{CC}/2$ , PLL_CP_GAIN = 1x		100		$\mu$ A
		$V_{CPout} = V_{CC}/2$ , PLL_CP_GAIN = 4x		400		
		$V_{CPout} = V_{CC}/2$ , PLL_CP_GAIN = 16x		1600		
		$V_{CPout} = V_{CC}/2$ , PLL_CP_GAIN = 32x		3200		

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>PLL (Continued)</b>						
$I_{\text{SINK}}^{\text{CPout}}$	Charge Pump Sink Current	$V_{\text{CPout}} = V_{\text{CC}}/2$ , PLL_CP_GAIN = 1x		-100		$\mu\text{A}$
		$V_{\text{CPout}} = V_{\text{CC}}/2$ , PLL_CP_GAIN = 4x		-400		
		$V_{\text{CPout}} = V_{\text{CC}}/2$ , PLL_CP_GAIN = 16x		-1600		
		$V_{\text{CPout}} = V_{\text{CC}}/2$ , PLL_CP_GAIN = 32x		-3200		
$I_{\text{CPout}}^{\text{TRI}}$	Charge Pump TRI-STATE Current	$0.5 \text{ V} < V_{\text{CPout}} < V_{\text{CC}} - 0.5 \text{ V}$		2	10	nA
$I_{\text{CPout}}^{\% \text{MIS}}$	Magnitude of Charge Pump Sink vs. Source Current Mismatch	$V_{\text{CPout}} = V_{\text{CC}} / 2$ $T_{\text{A}} = 25^{\circ}\text{C}$		3		%
$I_{\text{CPout}}^{\text{VTUNE}}$	Magnitude of Charge Pump Current vs. Charge Pump Voltage Variation	$0.5 \text{ V} < V_{\text{CPout}} < V_{\text{CC}} - 0.5 \text{ V}$ $T_{\text{A}} = 25^{\circ}\text{C}$		4		%
$I_{\text{CPout}}^{\text{TEMP}}$	Magnitude of Charge Pump Current vs. Temperature Variation			4		%
PN10kHz	PLL 1/f Noise at 10 kHz Offset (Note 5) Normalized to 1 GHz Output Frequency	PLL_CP_GAIN = 1x		-117		dBc/Hz
		PLL_CP_GAIN = 32x		-122		
PN1Hz	Normalized Phase Noise Contribution (Note 6)	PLL_CP_GAIN = 1x		-219		dBc/Hz
		PLL_CP_GAIN = 32x		-224		
<b>VCO</b>						
$f_{\text{Fout}}$	VCO Tuning Range	LMK03000/LMK03000C	1185		1296	MHz
		LMK03001/LMK03001C	1470		1570	
$ \Delta T_{\text{CL}} $	Allowable Temperature Drift for Continuous Lock	After programming R15 for lock, no changes to output configuration are permitted to guarantee continuous lock. (Note 7)			125	$^{\circ}\text{C}$
$P_{\text{Fout}}$	Output Power to a 50 $\Omega$ load driven by Fout	LMK03000/LMK03000C; $T_{\text{A}} = 25^{\circ}\text{C}$		3.3		dBm
		LMK03001/LMK03001C; $T_{\text{A}} = 25^{\circ}\text{C}$		2.7		
$K_{\text{Vtune}}$	Fine Tuning Sensitivity (The lower sensitivity indicates the typical sensitivity at the lower end of the tuning range, the higher sensitivity at the higher end of the tuning range)	LMK03000/LMK03000C		7 to 9		MHz/V
		LMK03001/LMK03001C		9 to 11		
$J_{\text{RMS}}^{\text{Fout}}$	Fout RMS Period Jitter	LMK03000/LMK03001 12 kHz to 20 MHz bandwidth		800		fs
		LMK03000C/LMK03001C 12 kHz to 20 MHz bandwidth		400		fs
$L(f)_{\text{Fout}}$	Fout Single Side Band Phase Noise	LMK03000C $f_{\text{Fout}} = 1296 \text{ MHz}$ (Note 8)	10 kHz Offset		-91.4	dBc/Hz
			100 kHz Offset		-116.8	
			1 MHz Offset		-137.8	
			10 MHz Offset		-156.9	
		LMK03000C $f_{\text{Fout}} = 1185 \text{ MHz}$ (Note 8)	10 kHz Offset		-93.5	
			100 kHz Offset		-118.5	
			1 MHz Offset		-139.4	
			10 MHz Offset		-158.4	
		LMK03001C $f_{\text{Fout}} = 1570 \text{ MHz}$ (Note 8)	10 kHz Offset		-89.6	
			100 kHz Offset		-115.2	
			1 MHz Offset		-136.5	
			10 MHz Offset		-156.0	
		LMK03001C $f_{\text{Fout}} = 1470 \text{ MHz}$ (Note 8)	10 kHz Offset		-91.6	
			100 kHz Offset		-116.0	
			1 MHz Offset		-137.9	
			10 MHz Offset		-156.2	

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>Clock Distribution Section (Note 9) - LVDS Clock Outputs (CLKout0 to CLKout2)</b>						
Jitter <sub>ADD</sub>	Additive RMS Jitter (Note 9)	R <sub>L</sub> = 100 Ω Input Bus = 785 MHz Bandwidth = 12 kHz to 20 MHz	CLKoutX_MUX = Bypass		20	fs
			CLKoutX_MUX = Divided CLKoutX_DIV = 4		75	
t <sub>SKEW</sub>	CLKoutX to CLKoutY (Note 10)	Equal loading and identical channel configuration R <sub>L</sub> = 100 Ω	-30	±4	30	ps
V <sub>OD</sub>	Differential Output Voltage	R <sub>L</sub> = 100 Ω	250	350	450	mV
ΔV <sub>OD</sub>	Change in magnitude of V <sub>OD</sub> for complementary output states	R <sub>L</sub> = 100 Ω	-50		50	mV
V <sub>OS</sub>	Output Offset Voltage	R <sub>L</sub> = 100 Ω	1.070	1.25	1.370	V
ΔV <sub>OS</sub>	Change in magnitude of V <sub>OS</sub> for complementary output states	R <sub>L</sub> = 100 Ω	-35		35	mV
I <sub>SA</sub> I <sub>SB</sub>	Clock Output Short Circuit Current single ended	Single ended outputs shorted to GND	-24		24	mA
I <sub>SAB</sub>	Clock Output Short Circuit Current differential	Complementary outputs tied together	-12		12	mA
<b>Clock Distribution Section (Note 9) - LVPECL Clock Outputs (CLKout3 to CLKout7)</b>						
Jitter <sub>ADD</sub>	Additive RMS Jitter (Note 9)	R <sub>L</sub> = 100 Ω Input Bus = 785 MHz Integration Bandwidth = 12 kHz to 20 MHz	CLKoutX_MUX = Bypass		20	fs
			CLKoutX_MUX = Divided CLKoutX_DIV = 4		75	
t <sub>SKEW</sub>	CLKoutX to CLKoutY (Note 10)	Equal loading and identical channel configuration Termination = 50 Ω to V <sub>CC</sub> - 2 V	-30	±3	30	ps
V <sub>OH</sub>	Output High Voltage	Termination = 50 Ω to V <sub>CC</sub> - 2 V		V <sub>CC</sub> - 0.98		V
V <sub>OL</sub>	Output Low Voltage			V <sub>CC</sub> - 1.8		V
V <sub>OD</sub>	Differential Output Voltage		660	810	965	mV
<b>Digital LVTTTL Interfaces (Note 11)</b>						
V <sub>IH</sub>	High-Level Input Voltage		2.0		V <sub>CC</sub>	V
V <sub>IL</sub>	Low-Level Input Voltage				0.8	V
I <sub>IH</sub>	High-Level Input Current	V <sub>IH</sub> = V <sub>CC</sub>	-5.0		5.0	μA
I <sub>IL</sub>	Low-Level Input Current	V <sub>IL</sub> = 0	-40.0		5.0	μA
V <sub>OH</sub>	High-Level Output Voltage	I <sub>OH</sub> = -500 μA	V <sub>CC</sub> - 0.4			V
V <sub>OL</sub>	Low-Level Output Voltage	I <sub>OL</sub> = -500 μA			0.4	V
<b>Digital MICROWIRE Interfaces (Note 12)</b>						
V <sub>IH</sub>	High-Level Input Voltage		1.6		V <sub>CC</sub>	V
V <sub>IL</sub>	Low-Level Input Voltage				0.4	V
I <sub>IH</sub>	High-Level Input Current	V <sub>IH</sub> = V <sub>CC</sub>	-5.0		5.0	μA
I <sub>IL</sub>	Low-Level Input Current	V <sub>IL</sub> = 0	-5.0		5.0	μA

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>MICROWIRE Timing</b>						
$t_{CS}$	Data to Clock Set Up Time	See Data Input Timing	25			ns
$t_{CH}$	Data to Clock Hold Time	See Data Input Timing	8			ns
$t_{CWH}$	Clock Pulse Width High	See Data Input Timing	25			ns
$t_{CWL}$	Clock Pulse Width Low	See Data Input Timing	25			ns
$t_{ES}$	Clock to Enable Set Up Time	See Data Input Timing	25			ns
$t_{CES}$	Enable to Clock Set Up Time	See Data Input Timing	25			ns
$t_{EWH}$	Enable Pulse Width High	See Data Input Timing	25			ns

**Note 4:** See Section 3.5 for more current consumption / power dissipation information.

**Note 5:** A specification in modeling PLL in-band phase noise is the 1/f flicker noise,  $L_{PLL\_flicker}(f)$ , which is dominant close to the carrier. Flicker noise has a 10 dB/decade slope. PN10kHz is normalized to a 10 kHz offset and a 1 GHz carrier frequency.  $PN10kHz = L_{PLL\_flicker}(10\text{ kHz}) - 20\log(F_{out} / 1\text{ GHz})$ , where  $L_{PLL\_flicker}(f)$  is the single side band phase noise of only the flicker noise's contribution to total noise,  $L(f)$ . To measure  $L_{PLL\_flicker}(f)$  it is important to be on the 10 dB/decade slope close to the carrier. A high compare frequency and a clean crystal are important to isolating this noise source from the total phase noise,  $L(f)$ .  $L_{PLL\_flicker}(f)$  can be masked by the reference oscillator performance if the source is low power or noisy. The total PLL inband phase noise performance is the sum of  $L_{PLL\_flicker}(f)$  and  $L_{PLL\_flat}(f)$ .  $L_{PLL\_flicker}(f)$  can be masked by the reference oscillator performance if the source is low power or noisy. The total PLL inband phase noise performance is the sum of  $L_{PLL\_flicker}(f)$  and  $L_{PLL\_flat}(f)$ .

**Note 6:** A specification in modeling PLL in-band phase noise is the Normalized Phase Noise Contribution,  $L_{PLL\_flat}(f)$ , of the PLL and is defined as:  $PN1Hz = L_{PLL\_flat}(f) - 20\log(N) - 10\log(F_{comp})$ .  $L_{PLL\_flat}(f)$  is the single side band phase noise measured at an offset frequency,  $f$ , in a 1 Hz Bandwidth and  $F_{comp}$  is the comparison frequency of the synthesizer.  $L_{PLL\_flat}(f)$  contributes to the total noise,  $L(f)$ . To measure  $L_{PLL\_flat}(f)$  the offset frequency,  $f$ , must be chosen sufficiently smaller than the loop bandwidth of the PLL, and yet large enough to avoid a substantial noise contribution from the reference and flicker noise.  $L_{PLL\_flat}(f)$  can be masked by the reference oscillator performance if the source is low power or noisy.

**Note 7:** Allowable Temperature Drift for Continuous Lock is how far the temperature can drift in either direction and stay in lock from the ambient temperature and programmed state at which the device was when register R15 was programmed. The action of programming the R15 register, even to the same value, activates a frequency calibration routine. This implies that the part will work over the entire frequency range, but if the temperature drifts more than the maximum allowable drift for continuous lock, then it will be necessary to reload the R15 register to ensure that it stays in lock. Regardless of what temperature the part was initially programmed at, the ambient temperature can never drift outside the range of  $-40\text{ }^{\circ}\text{C} \leq T_A \leq 85\text{ }^{\circ}\text{C}$  without violating specifications. For this specification to be valid the programmed state of the device must not change after R15 is programmed.

**Note 8:** VCO phase noise is measured assuming the VCO is the dominant noise source due to a 75 Hz loop bandwidth. Over frequency, the phase noise typically varies by 1 to 2 dB, with the worst case performance typically occurring at the highest frequency. Over temperature, the phase noise typically varies by 1 to 2 dB, assuming the part is not reloaded. Re-programming R15 will run the frequency calibration routine for optimum phase noise.

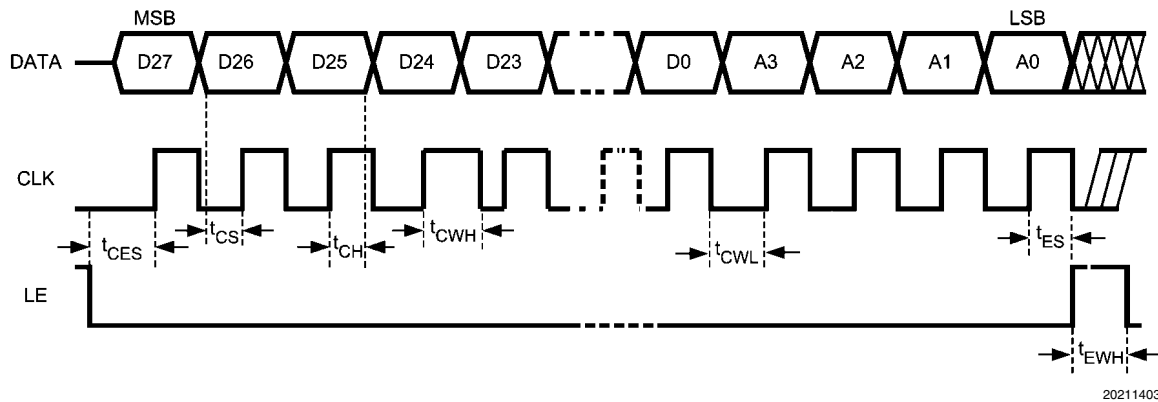
**Note 9:** The Clock Distribution Section includes all parts of the device except the PLL and VCO sections. Typical Additive Jitter specifications apply to the clock distribution section only and is in RMS form addition to the jitter from the VCO.

**Note 10:** Specification is guaranteed by characterization and is not tested in production.

**Note 11:** Applies to GOE, LD, and SYNC\*.

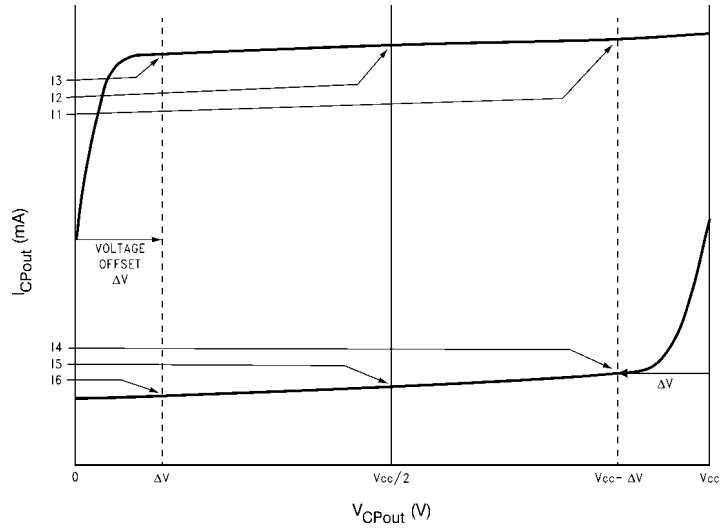
**Note 12:** Applies to uWireCLK, uWireDATA, and uWireLE.

## Serial Data Timing Diagram



Data bits set on the DATA signal are clocked into a shift register, MSB first, on each rising edge of the CLK signal. On the rising edge of the LE signal, the data is sent from the shift register to the addressed register determined by the LSB bits. After the programming is complete the CLK, DATA, and LE signals should be returned to a low state.

## Charge Pump Current Specification Definitions



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I1 = Charge Pump Sink Current at  $V_{CPout} = V_{cc} - \Delta V$

I2 = Charge Pump Sink Current at  $V_{CPout} = V_{cc}/2$

I3 = Charge Pump Sink Current at  $V_{CPout} = \Delta V$

I4 = Charge Pump Source Current at  $V_{CPout} = V_{cc} - \Delta V$

I5 = Charge Pump Source Current at  $V_{CPout} = V_{cc}/2$

I6 = Charge Pump Source Current at  $V_{CPout} = \Delta V$

$\Delta V$  = Voltage offset from the positive and negative supply rails. Defined to be 0.5 V for this device.

### Charge Pump Output Current Magnitude Variation vs. Charge Pump Output Voltage

$$I_{CPout} \text{ Vs } V_{CPout} = \frac{|I1| - |I3|}{|I1| + |I3|} \times 100\%$$

$$= \frac{|I4| - |I6|}{|I4| + |I6|} \times 100\%$$

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### Charge Pump Sink Current vs. Charge Pump Output Source Current Mismatch

$$I_{CPout} \text{ Sink Vs } I_{CPout} \text{ Source} = \frac{|I2| - |I5|}{|I2| + |I5|} \times 100\%$$

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### Charge Pump Output Current Magnitude Variation vs. Temperature

$$I_{CPout} \text{ Vs } T_A = \frac{|I2|_{T_A} - |I2|_{T_A=25^\circ C}}{|I2|_{T_A=25^\circ C}} \times 100\%$$

$$= \frac{|I5|_{T_A} - |I5|_{T_A=25^\circ C}}{|I5|_{T_A=25^\circ C}} \times 100\%$$

20211434



## 1.0 Functional Description

The LMK03000/LMK03000C/LMK03001/LMK03001C precision clock conditioners combine the functions of jitter cleaning/reconditioning, multiplication, and distribution of a reference clock. The devices integrate a Voltage Controlled Oscillator (VCO), a high performance Integer-N Phase Locked Loop (PLL), a partially integrated loop filter, three LVDS, and five LVPECL clock output distribution blocks.

When configured as a clock generator with a wide loop bandwidth, a high phase detector frequency, and a low noise clock source the LMK03000C/LMK03001C features jitter performance of 200 fs RMS (10 Hz - 20 MHz). When configured as a jitter cleaner, the LMK03000C/LMK03001C features jitter performance of 400 fs RMS (12 kHz - 20 MHz) and the LMK03000C/LMK03001C 800 fs RMS (12 kHz - 20 MHz).

The devices include internal 3rd and 4th order poles to simplify loop filter design and improve spurious performance. The 1st and 2nd order poles are off-chip to provide flexibility for the design of various loop filter bandwidths.

Two VCO frequency plans are available for each performance grade. The LMK03000 and LMK03000C include a 1.24 GHz VCO. The LMK03001 and LMK03001C include a 1.52 GHz VCO. The VCO output is optionally accessible on the Fout port. Internally, the VCO output goes through an Input Divider to feed the various clock distribution blocks.

Each clock distribution block includes a programmable divider, a phase synchronization circuit, a programmable delay, a clock output mux, and an LVDS or LVPECL output buffer. This allows multiple integer-related and phase-adjusted copies of the reference to be distributed to eight system components.

The clock conditioners come in a 48-pin LLP package and are footprint compatible with other clocking devices in the same family.

### 1.1 BIAS PIN

To properly use the device, bypass Bias (pin 36) with a low leakage 1  $\mu$ F capacitor connected to Vcc. This is important for low noise performance.

### 1.2 LDO BYPASS

To properly use the device, bypass LDObyp1 (pin 9) with a 10  $\mu$ F capacitor and LDObyp2 (pin 10) with a 0.1  $\mu$ F capacitor.

### 1.3 OSCILLATOR INPUT PORT (OSCin, OSCin\*)

The purpose of OSCin is to provide the PLL with a reference signal. The OSCin port must be AC coupled, refer to the System Level Diagram in the Application Information section. The OSCin port may be driven single ended by AC grounding OSCin\* with a 0.1  $\mu$ F capacitor.

### 1.4 LOW NOISE, FULLY INTEGRATED VCO

The LMK03000/LMK03000C/LMK03001/LMK03001C devices contain a fully integrated VCO. In order for proper operation the VCO uses a frequency calibration algorithm. The frequency calibration algorithm is activated any time that the R15 register is programmed. Once R15 is programmed the temperature may not drift more than the maximum allowable drift for continuous lock,  $\Delta T_{CL}$ , or else the VCO is not guaranteed to stay in lock.

For the frequency calibration algorithm to work properly OSCin must be driven by a valid signal when R15 is programmed.

### 1.5 CLKout DELAYS

Each individual clock output includes a delay adjustment. Clock output delay registers (CLKoutX\_DLY) support a 150 ps step size and range from 0 to 2250 ps of total delay.

### 1.6 LVDS/LVPECL OUTPUTS

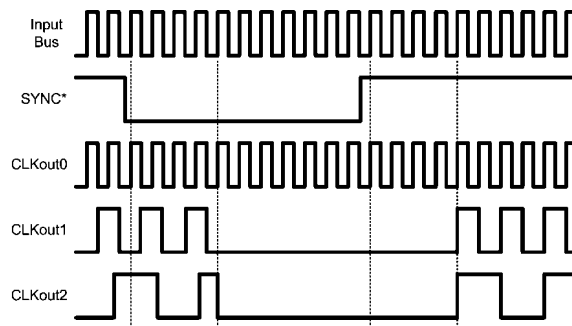
Each LVDS or LVPECL output may be disabled individually by programming the CLKoutX\_EN bits. All the outputs may be disabled simultaneously by pulling the GOE pin low or programming EN\_CLKout\_Global to 0.

### 1.7 GLOBAL CLOCK OUTPUT SYNCHRONIZATION

The SYNC\* synchronizes the clock outputs. When SYNC\* is held in a logic low state, the outputs are also held in a logic low state. When SYNC\* goes high, the clock outputs are activated and will transition to a high state simultaneously.

SYNC\* must be held low for greater than one clock cycle of the Input Channel Bus. Once this low event has been registered, the outputs will not reflect the low state for four more cycles. Similarly once SYNC\* becomes high, the outputs will not simultaneously transition high until four more Input Channel Bus clock cycles have passed. See the timing diagram below for further detail. In the timing diagram below the channels are programmed as: CLKout0\_MUX = Bypassed, CLKout1\_MUX = Divided, CLKout1\_DIV = 2, CLKout2\_MUX = Divided, CLKout2\_DIV = 4.

#### SYNC\* Timing Diagram



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### 1.8 CLKout OUTPUT STATES

Each clock output may be individually enabled with the CLKoutX\_EN bits. Each individual output enable control bit is gated with the Global Output Enable input pin (GOE) and the Global Output Enable bit (EN\_CLKout\_Global).

All clock outputs can be disabled simultaneously if the GOE pin is pulled low by an external signal or EN\_CLKout\_Global is set to 0.

CLKoutX_EN bit	EN_CLKout_Global bit	GOE pin	Clock X Output State
1	1	0	Low
Don't care	0	Don't care	Off
0	Don't care	Don't care	Off
1	1	High	Enabled

When an LVDS output is in the Off state, the outputs are at a voltage of approximately 1.5 volts. When an LVPECL output is in the Off state, the outputs are at a voltage of approximately 1 volt.

### 1.9 GLOBAL OUTPUT ENABLE AND LOCK DETECT

The GOE pin provides an internal pull-up resistor. If it is un-terminated externally, the clock output states are determined by the Clock Output Enable bits (CLKoutX\_EN) and the EN\_CLKout\_Global bit.

By programming the PLL\_MUX register to Digital Lock Detect Active High (See 2.5.2), the Lock Detect (LD) pin can be connected to the GOE pin in which case all outputs are set low automatically if the synthesizer is not locked.

## 2.0 General Programming Information

The LMK03000/LMK03000C/LMK03001/LMK03001C devices are programmed using several 32-bit registers which control the device's operation. The registers consist of a data field and an address field. The last 4 register bits, ADDR[3:0] form the address field. The remaining 28 bits form the data field DATA[27:0].

During programming LE is low, serial data is clocked in on the rising edge of clock (MSB first). When LE goes high, data is transferred to the register bank selected by the address field. Only registers R0 to R7, R11, and R13 to R15 need to be programmed for proper device operation.

For the frequency calibration algorithm to work properly OSCin must be driven by a valid signal when R15 is programmed.

### 2.1 RECOMMENDED PROGRAMMING SEQUENCE

The recommended programming sequence involves programming R0 with the reset bit set (RESET = 1) to ensure the device is in a default state. It is not necessary to program R0 again, but if R0 is programmed again, the reset bit is programmed clear (RESET = 0). Registers are programmed in order with R15 being the last register programmed. An example programming sequence is shown below.

- R0 with the reset bit set (RESET = 1). This ensures the device is in a default state. When the reset bit is set in R0, the other R0 bits are ignored.
  - If R0 is programmed again, reset bit is programmed clear (RESET = 0).
- R0 to R7 as necessary with desired channels with appropriate enable, mux, divider, and delay settings.
- R11 with DIV4 setting if necessary.
- R13 with oscillator input frequency and internal loop filter values
- R14 with Fout enable bit, global clock output bit, power down setting, PLL mux setting, and PLL R divider.
- R15 with PLL charge pump gain, input divider, and PLL N divider.

Any changes to the PLL R divider require R15 to be programmed again to active the frequency calibration routine.

**LMK03000/LMK03000C/LMK03001/LMK03001C Register Map**

Register	31	30	29	28	27	26	25	24	23	22	21	20	19	18	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
	Data [27:0]																A3											A2	A1	A0		
R0	RESET	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0
R1	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0
R2	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0
R3	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0
R4	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0
R5	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0
R6	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0
R7	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0

Register	31	30	29	28	27	26	25	24	23	22	21	20	19	18	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0		
R11	0	0	0	0	0	0	0	0	1	0	0	0	0	0	0	0	D <sub>4</sub>	0	0	0	0	0	0	0	0	0	0	0	0	0	0	1	1	
R13	0	0	0	0	0	0	1	0	1	0	0	0	0	0	0	0	OSCin_FREQ [7:0]	0	VCO_ R4_LF [2:0]	0	VCO_ R3_LF [2:0]	0	VCO_ C3_C4_LF [3:0]	0	1	0	1	0	1	0	1	1		
R14	0	0	0	0	EN_Fout	POWERDOWN	0	0	0	PLL_ MUX [3:0]	PLL_R [11:0]	PLL_N [17:0]	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	1	1	0	0	
R15	PLL_ CP_ GAIN [1:0]	INPUT_DIV [3:0]			PLL_N [17:0]											0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	1	1	1

**2.2 REGISTER R0 to R7**

Registers R0 through R7 control the eight clock output pins. Register R0 controls CLKout0, Register R1 controls CLKout1, and so on. There is one additional bit in register R0 called RESET. Aside from this, the functions of these bits are identical. The X in CLKoutX\_MUX, CLKoutX\_DIV, CLKoutX\_DLY, and CLKoutX\_EN denote the actual clock output which may be from 0 to 7.

**2.2.1 RESET bit -- R0 only**

This bit is only in register R0. The use of this bit is optional and it should be set to '0' if not used. Setting this bit to a '1' forces all registers to their power on reset condition. If this bit is set, all other R0 bits are ignored and R0 needs to be programmed again if used with its proper values and RESET = 0.

**2.2.2 CLKoutX\_MUX[1:0] -- Clock Output Multiplexers**

These bits control the Clock Output Multiplexer for each pin. Changing between the different modes changes the blocks in the signal path and therefore incurs a delay relative to the bypass mode. The different MUX modes and associated delays are listed below.

CLKoutX_MUX[1:0]	Mode	Added Delay Relative to Bypass Mode
0	Bypassed	0 ps
1	Divided	100 ps
2	Delayed	400 ps (In addition to the programmed delay)
3	Divided and Delayed	500 ps (In addition to the programmed delay)

**2.2.3 CLKoutX\_DIV[7:0] -- Clock Output Dividers**

These bits control the clock output divider value. In order for these dividers to be active, the respective CLKoutX\_MUX (See 2.2.2) bit must be set to either "Divided" or "Divided and Delayed" mode. After all the dividers are programmed, the SYNC\* pin must be used to ensure that all edges of the clock output pins are aligned (See 1.7). The Clock Output Dividers follow the Input Divider so the final clock divide for an output is Input Divider \* Clock Output Divider. By adding the divider block to the output path a fixed delay of approximately 100 ps is incurred.

The actual Clock Output Divide value is twice the binary value programmed as listed in the table below.

CLKoutX_DIV[7:0]								Clock Output Divider value
0	0	0	0	0	0	0	0	Invalid
0	0	0	0	0	0	0	1	2
0	0	0	0	0	0	1	0	4
0	0	0	0	0	0	1	1	6
0	0	0	0	0	1	0	0	8
0	0	0	0	0	1	0	1	10
.	.	.	.	.	.	.	.	...
1	1	1	1	1	1	1	1	510

### 2.2.4 CLKoutX\_DLY[3:0] -- Clock Output Delays

These bits control the delay stages for each clock output pin. In order for these delays to be active, the respective CLKoutX\_MUX (See 2.2.2) bit must be set to either "Delayed" or "Divided and Delayed" mode. By adding the delay block to the output path a fixed delay of approximately 400 ps is incurred in addition to the delay shown in the table below.

CLKoutX_DLY[3:0]	Delay (ps)
0	0
1	150
2	300
3	450
4	600
5	750
6	900
7	1050
8	1200
9	1350
10	1500
11	1650
12	1800
13	1950
14	2100
15	2250

### 2.2.5 CLKoutX\_EN bit -- Clock Output Enables

These bits control whether an individual clock output is enabled or not. If the EN\_CLKout\_Global bit (See 2.5.4) is set to zero or if GOE pin is held low, all CLKoutX\_EN bit states will be ignored and all clock outputs will be disabled. See 1.8 for more information on CLKout states.

CLKoutX_EN bit	EN_CLKout_Global bit	GOE pin	CLKoutX State
0	1	0	Disabled
1	1	0	Enabled

## 2.3 REGISTER R11

This register only has one bit and only needs to be programmed in the case that the OSCin frequency is greater than 20 MHz and digital lock detect is used. Otherwise, it is automatically defaulted to the correct values.

### 2.3.1 DIV4

This bit divides the frequency presented to the digital lock detect circuitry by 4. It is necessary to get a reliable output from the digital lock detect output in the case of a OSCin frequency greater than 20 MHz.

DIV4	Frequency Presented to the Digital Lock Detect Circuitry
0 (Default)	Not divided
1	Divided by 4

## 2.4 REGISTER R13

### 2.4.1 VCO\_C3\_C4\_LF[3:0] -- Value for Internal Loop Filter Capacitors C3 and C4

These bits control the capacitor values for C3 and C4 in the internal loop filter.

VCO_C3_C4_LF[3:0]	Loop Filter Capacitors	
	C3 (pF)	C4 (pF)
0	0	10
1	0	60
2	50	10
3	0	110
4	50	110
5	100	110
6	0	160
7	50	160
8	100	10
9	100	60
10	150	110
11	150	60
12 to 15	Invalid	

### 2.4.2 VCO\_R3\_LF[2:0] -- Value for Internal Loop Filter Resistor R3

These bits control the R3 resistor value in the internal loop filter. The recommended setting for VCO\_R3\_LF[2:0] = 0 for optimum phase noise and jitter.

VCO_R3_LF[2:0]	R3 Value (k $\Omega$ )
0	Low (< 100 $\Omega$ )
1	10
2	20
3	30
4	40
5 to 7	Invalid

### 2.4.3 VCO\_R4\_LF[2:0] -- Value for Internal Loop Filter Resistor R4

These bits control the R4 resistor value in the internal loop filter. The recommended setting for VCO\_R4\_LF[2:0] = 0 for optimum phase noise and jitter.

VCO_R4_LF[2:0]	R4 Value (k $\Omega$ )
0	Low (< 100 $\Omega$ )
1	10
2	20
3	30
4	40
5 to 7	Invalid



#### 2.4.4 OSCin\_FREQ[7:0] -- Oscillator Input Calibration Adjustment

These bits are to be programmed to the OSCin frequency. If the OSCin frequency is not an integral multiple of 1 MHz, then round to the closest value.

OSCin_FREQ[7:0]	OSCin Frequency
1	1 MHz
2	2 MHz
...	...
200	200 MHz
201 to 255	Invalid

### 2.5 REGISTER R14

#### 2.5.1 PLL\_R[11:0] -- R Divider Value

These bits program the PLL R Divider and are programmed in binary fashion. Any changes to PLL\_R require R15 to be programmed again to active the frequency calibration routine.

PLL_R[11:0]											PLL R Divide Value	
0	0	0	0	0	0	0	0	0	0	0	0	Invalid
0	0	0	0	0	0	0	0	0	0	0	1	1
0	0	0	0	0	0	0	0	0	0	1	0	2
.	.	.	.	.	.	.	.	.	.	.	.	...
1	1	1	1	1	1	1	1	1	1	1	1	4095

#### 2.5.2 PLL\_MUX[3:0] -- Multiplexer Control for LD Pin

These bits set the output mode of the LD pin. The table below lists several different modes.

PLL_MUX[3:0]	Output Type	LD Pin Function
0	Hi-Z	Disabled
1	Push-Pull	Logic High
2	Push-Pull	Logic Low
3	Push-Pull	Digital Lock Detect (Active High)
4	Push-Pull	Digital Lock Detect (Active Low)
5	Push-Pull	Analog Lock Detect
6	Open Drain NMOS	Analog Lock Detect
7	Open Drain PMOS	Analog Lock Detect
8	Push-Pull	N Divider Output (Very Low Duty Cycle)
9	Push-Pull	N Divider Output/2 (50% Duty Cycle)
10	Push-Pull	R Divider Output (Very Low Duty Cycle)
11	Push-Pull	R Divider Output/2 (50% Duty Cycle)
12 to 15	Invalid	

#### 2.5.3 POWERDOWN bit -- Device Power Down

This bit can power down the device. Enabling this bit powers down the entire chip and all blocks, regardless of the state of any of the other bits or pins.

POWERDOWN bit	Mode
0	Normal Operation
1	Entire Chip Powered Down

### 2.5.4 EN\_CLKout\_Global bit -- Global Clock Output Enable

This bit overrides the individual CLKoutX\_EN bits (See 2.2.5). When this bit is set to 0, all clock outputs are disabled, regardless of the state of any of the other bits or pins. See 1.8 for more information on CLKout states.

EN_CLKout_Global bit	Clock Outputs
0	All Off
1	Normal Operation

### 2.5.5 EN\_Fout bit -- Fout port enable

This bit enables the Fout pin.

EN_Fout bit	Fout Pin Status
0	Disabled
1	Enabled

## 2.6 Register R15

Programming R15 also activates the frequency calibration routine.

### 2.6.1 PLL\_N[17:0] -- PLL N Divider

These bits program the divide value for the PLL N Divider. The PLL N Divider follows the Input Divider and precedes the PLL phase detector. Since the Input Divider is also in the feedback path from the VCO to the PLL Phase Detector, the total N divide value,  $N_{Total}$ , is also influenced by the Input Divider value.  $N_{Total} = \text{PLL N Divider} * \text{Input Divider}$ . The VCO frequency is calculated as,  $f_{VCO} = f_{OSCin} * \text{PLL N Divider} * \text{Input Divider} / R$ . Since the PLL N divider is a pure binary counter, there are no illegal divide values for PLL\_N[17:0].

PLL_N[17:0]																PLL N Divider Value	
0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	Invalid
0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	1	1
.	.	.	.	.	.	.	.	.	.	.	.	.	.	.	.	.	...
1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	262143

### 2.6.2 INPUT\_DIV[3:0] -- Input Divider

These bits program the divide value for the Input Divider. The Input Divider follows the VCO output and precedes the clock distribution blocks. Since the Input Divider is in the feedback path from the VCO to the PLL phase detector the Input Divider contributes to the total N divide value,  $N_{Total}$ .  $N_{Total} = \text{PLL N Divider} * \text{Input Divider}$ . The Input Divider can not be bypassed. See 2.5.1 (PLL N Divider) for more information on setting the VCO frequency.

INPUT_DIV[3:0]				Input Divider Value
0	0	0	0	Invalid
0	0	0	1	Invalid
0	0	1	0	2
0	0	1	1	3
0	1	0	0	4
0	1	0	1	5
0	1	1	0	6
0	1	1	1	7
1	0	0	0	8
1	0	0	1	Invalid
.	.	.	.	...
1	1	1	1	Invalid

### 2.6.3 PLL\_CP\_GAIN[1:0] -- PLL Charge Pump Gain

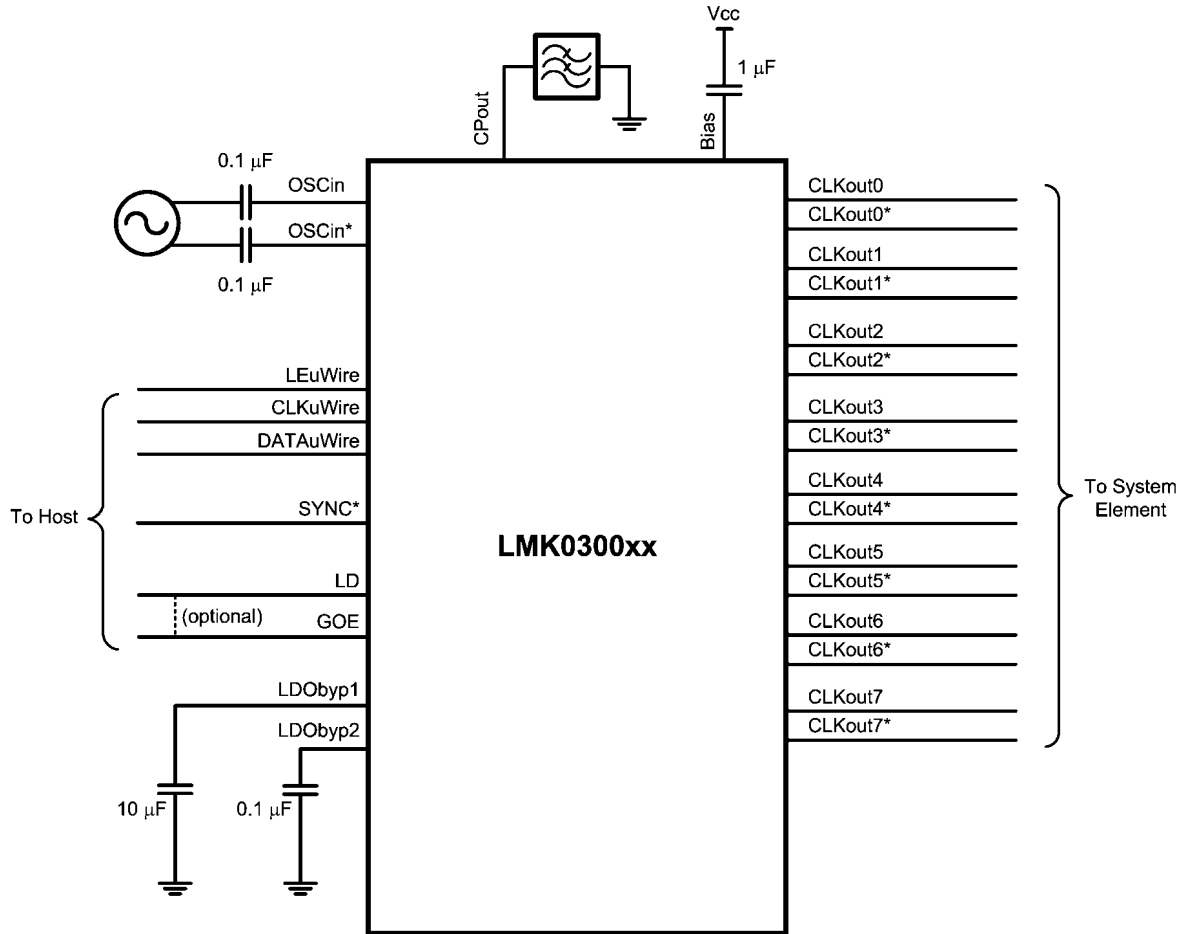
These bits set the charge pump gain of the PLL.

PLL_CP_GAIN[1:0]	Charge Pump Gain
0	1x
1	4x
2	16x
3	32x

### 3.0 Application Information

#### 3.1 SYSTEM LEVEL DIAGRAM

The following shows the LMK300xx in a typical application. In this setup the clock may be multiplied, reconditioned, and redistributed. The first and second pole of the loop filter are external. The third and fourth poles are integrated.



20211470

FIGURE 1. Typical Application

#### 3.2 BIAS PIN

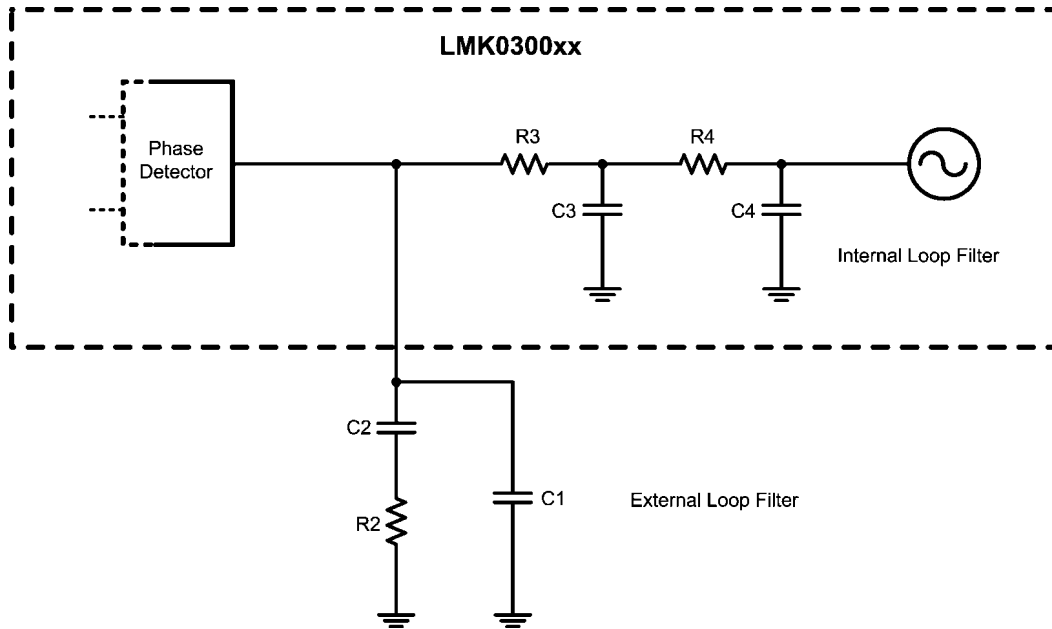
To properly use the device, bypass Bias (pin 36) with a low leakage 1 μF capacitor connected to Vcc. This is important for low noise performance.

#### 3.3 LDO BYPASS

To properly use the device, bypass LDObyp1 (pin 9) with a 10 μF capacitor and LDObyp2 (pin 10) with a 0.1 μF capacitor.

### 3.4 LOOP FILTER

The internal charge pump is directly connected to the integrated loop filter components. The first and second pole of the loop filter are externally attached as shown in *Figure 2*. When the loop filter is designed, it must be stable over the entire frequency band, meaning that the changes in  $K_{V_{tune}}$  from the low to high band specification will not make the loop filter unstable.



20211471

FIGURE 2. Loop Filter

### 3.5 CURRENT CONSUMPTION / POWER DISSIPATION CALCULATIONS

Due to the myriad of possible configurations the follow table serves to provide enough information to allow the user to calculate estimated current consumption of the device. Unless otherwise noted  $V_{CC} = 3.3\text{ V}$ ,  $T_A = 25\text{ }^\circ\text{C}$ .

Block	Condition	Current Consumption at 3.3 V (mA)	Power Dissipated in IC (mW)	Power Dissipated in LVPECL emitter resistors (mW)
Entire device, core current	All outputs off; No LVPECL emitter resistors connected	86.0	283.8	-
Low channel buffer (internal)	The low channel buffer is enabled anytime one of CLKout0 through CLKout3 are enabled	9	29.7	-
High channel buffer (internal)	The high channel buffer is enabled anytime one of the CLKout4 through CLKout7 are enabled	9	29.7	-
Output buffers	Fout buffer, EN_Fout = 1	14.5	47.8	-
	LVDS output, bypass mode	17.8	58.7	-
	LVPECL output, bypass mode (includes 120 $\Omega$ emitter resistors)	40	72	60
	LVPECL output, disabled mode (includes 120 $\Omega$ emitter resistors)	17.4	38.3	19.1
	LVPECL output, disabled mode. No emitter resistors placed; open outputs	0	0	-
Divide circuitry per output	Divide enabled, divide = 2	5.3	17.5	-
	Divide enabled, divide > 2	8.5	28.0	-
Delay circuitry per output	Delay enabled, delay < 8	5.8	19.1	-
	Delay enabled, delay > 7	9.9	32.7	-
Entire device	CLKout0 & CLKout4 enabled in bypass mode	161.8	474	60
	CLKout0 & CLKout4 enabled in bypass mode (no emitter resistors placed)	144.4	476.5	-

From Table 3.5 the current consumption can be calculated in any configuration. For example, the current for the entire chip with 1 LVDS (CLKout0) & 1 LVPECL (CLKout4) output in bypass mode can be calculated by adding up the following blocks: core current, low channel buffer, high channel buffer, one LVDS output buffer current, and one LVPECL output buffer current. There will also be one LVPECL output drawing emitter current, but some of the power from the current draw is dissipated in the external 120  $\Omega$  resistors which doesn't add to the power dissipation budget for the IC. If delays or divides are switched in, then the additional current for these stages needs to be added as well.

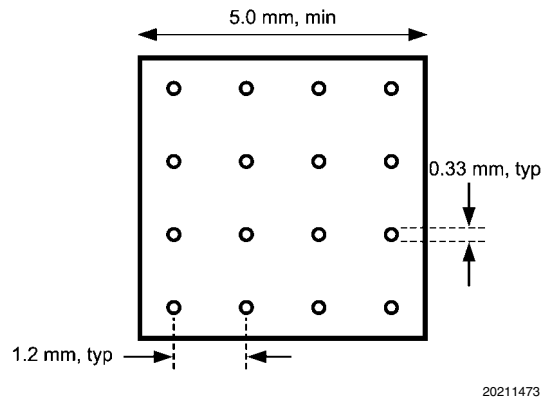
For power dissipated by the IC, the total current entering the IC is multiplied by the voltage at the IC minus the power dissipated in any emitter resistors connected to any of the LVPECL outputs. If no emitter resistors are connected to the LVPECL outputs, this power will be 0 watts. For example, in the case of 1 LVDS (CLKout0) & 1 LVPECL (CLKout4) operating at 3.3 volts, we calculate  $3.3\text{ V} * (86 + 9 + 9 + 17.8 + 40)\text{ mA} = 3.3\text{ V} * 161.8\text{ mA} = 533.9\text{ mW}$ . Because the LVPECL output (CLKout4) has the emitter resistors hooked up and the power dissipated by these resistors is 60 mW, the total IC power dissipation is  $533.9\text{ mW} - 60\text{ mW} = 473.9\text{ mW}$ .

When the LVPECL output is active,  $\sim 1.9\text{ V}$  is the average voltage on each output as calculated from the LVPECL Voh & Vol typical specification. Therefore the power dissipated in each emitter resistor is approximately  $(1.9\text{ V})^2 / 120\text{ } \Omega = 30\text{ mW}$ . When the LVPECL output is disabled, the emitter resistor voltage is  $\sim 1.07\text{ V}$ . Therefore the power dissipated in each emitter resistor is approximately  $(1.07\text{ V})^2 / 120\text{ } \Omega = 9.5\text{ mW}$ .

### 3.6 THERMAL MANAGEMENT

Power consumption of the LMK0300XX can be high enough to require attention to thermal management. For reliability and performance reasons the die temperature should be limited to a maximum of  $125\text{ }^\circ\text{C}$ . That is, as an estimate,  $T_A$  (ambient temperature) plus LMK0300XX power consumption times  $\theta_{JA}$  should not exceed  $125\text{ }^\circ\text{C}$ .

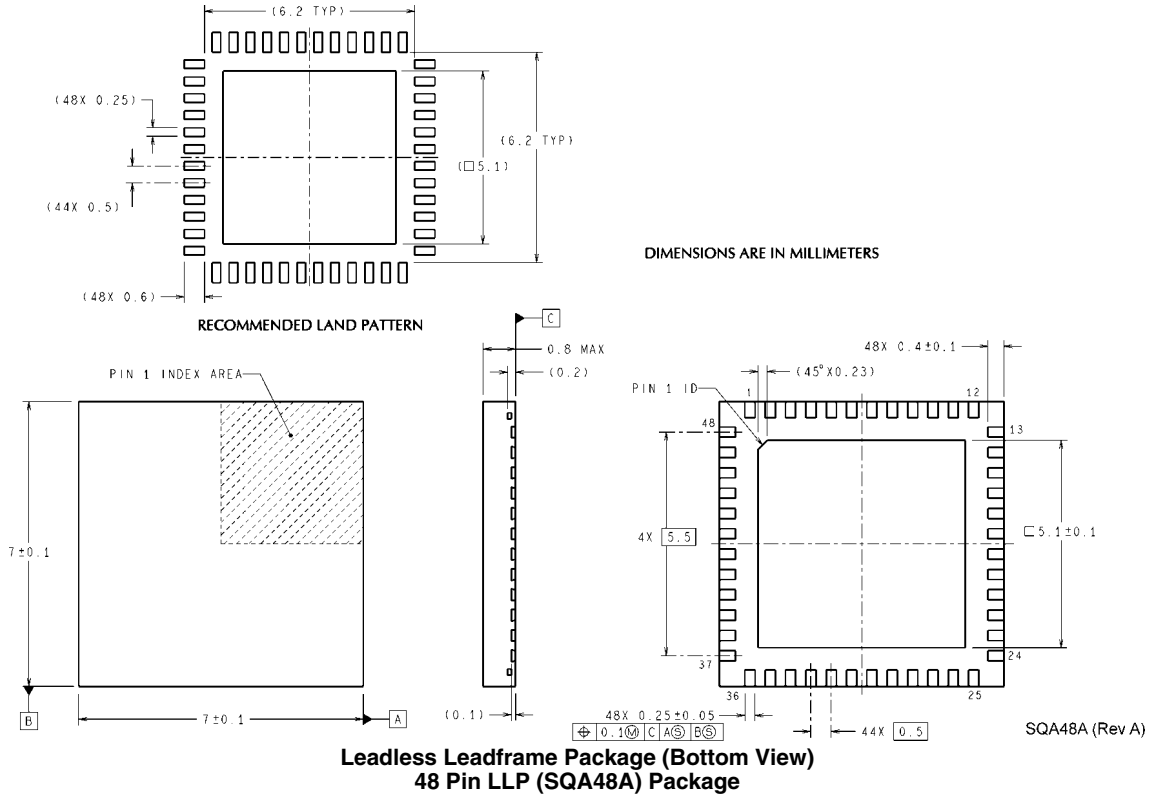
The package of the LMK0300XX has an exposed pad that provides the primary heat removal path as well as excellent electrical grounding to the printed circuit board. To maximize the removal of heat from the package a thermal land pattern including multiple vias to a ground plane must be incorporated on the PCB within the footprint of the package. The exposed pad must be soldered down to ensure adequate heat conduction out of the package. A recommended land and via pattern is shown in *Figure 3*. More information on soldering LLP packages can be obtained at [www.national.com](http://www.national.com).



**FIGURE 3. Recommended Land and Via Pattern**

To minimize junction temperature it is recommended that a simple heat sink be built into the PCB (if the ground plane layer is not exposed). This is done by including a copper area of about 2 square inches on the opposite side of the PCB from the LMK0300XX. This copper area may be plated or solder coated to prevent corrosion but should not have conformal coating (if possible), which could provide thermal insulation. The vias shown in *Figure 3* should connect these top and bottom copper layers and to the ground layer. These vias act as “heat pipes” to carry the thermal energy away from the device side of the board to where it can be more effectively dissipated.

**Physical Dimensions** inches (millimeters) unless otherwise noted



**Ordering Information**

Order Number	Package Marking	Packing	VCO Version	Performance Grade	LVDS Outputs	LVPECL Outputs
LMK03000ISQ	K03000 I	250 Unit Tape and Reel	1.24 GHz	800 fs	3	5
LMK03000ISQX	K03000 I	2500 Unit Tape and Reel	1.24 GHz	800 fs	3	5
LMK03001ISQ	K03001 I	250 Unit Tape and Reel	1.52 GHz	800 fs	3	5
LMK03001ISQX	K03001 I	2500 Unit Tape and Reel	1.52 GHz	800 fs	3	5
LMK03000CISQ	K03000CI	250 Unit Tape and Reel	1.24 GHz	400 fs	3	5
LMK03000CISQX	K03000CI	2500 Unit Tape and Reel	1.24 GHz	400 fs	3	5
LMK03001CISQ	K03001CI	250 Unit Tape and Reel	1.52 GHz	400 fs	3	5
LMK03001CISQX	K03001CI	2500 Unit Tape and Reel	1.52 GHz	400 fs	3	5



# Notes

LMK03000/LMK03000C/LMK03001/LMK03001C

## Notes

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Life support devices or systems are devices which (a) are intended for surgical implant into the body, or (b) support or sustain life and whose failure to perform when properly used in accordance with instructions for use provided in the labeling can be reasonably expected to result in a significant injury to the user. A critical component is any component in a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system or to affect its safety or effectiveness.

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